

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT****Complete if Known**

Application No.	10/661,037
Filing Date	September 12, 2003
First Named Inventor	John D. Hyde
Art Unit	2822
Examiner Name	Ida M. Soward
Attorney Docket Number	22524-17802

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	B3	EP 0 562 257 A1	09-29-1993	International Business Machines Corporation	
	B4	WO 00/60672 A1	10-12-2000	Koninklijke Philips Electronics N.V.	
	B5	WO 00/38239 A1	06-29-2000	Lattice Semiconductor Corporation	

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